

Notice of References Cited	Application/Control No. 10/673,040	Applicant(s)/Patent Under Reexamination THESS ET AL.	
	Examiner Neveen Abel-Jalil	Art Unit 2165	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,006,223	12-1999	Agrawal et al.	707/5
*	B	US-6,308,172	10-2001	Agrawal et al.	707/5
*	C	US-6,996,551	02-2006	Hellerstein et al.	706/48
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Jay Ayres, Johannes Gehrke, Tomi Yiu, and Jason Flannick. Sequential Pattern Mining using A bitmap Representation. Dept. of Computer Science, Cornell University. July 2002.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.